

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Change input to output voltage differential in 1.3, 1.4, $V_{REF}$ , $V_{RLINE}$ , $I_{ADJ}$ , and $\Delta I_{ADJ}$ conditions. Change $I_{LIM}$ test limits for conditions $(V_{IN} - V_{OUT}) = 2.5$ V from 0.05 A to 0.075 A. Add case outline Y (TO-39).	92-08-19	M. A. FRYE
B	Table I, current limit test, $I_{LIM}$ , $(V_{IN} - V_{OUT}) = 25$ V, delete "case X and U, at 0.075 A min" and substitute "case X at 0.05 A min" and "case U at 0.075 A min". Changes in accordance with NOR 5962-R034-94.	92-12-23	M. A. FRYE
C	Add case outline Z. Technical and editorial changes throughout.	94-08-09	M. A. FRYE
D	Table II, groups C and D end-point electrical parameters; delete subgroups "1, 2, 3" and substitute "1". Changes in accordance with NOR 5962-R044-99.	99-03-24	R. MONNIN
E	Add case outlines M and T. - ro	02-02-21	R. MONNIN
F	Remove max limits for the current limit test, $I_{LIM}$ , in table I. - rrp	07-07-23	ROBERT M. HEBER
G	Add footnote to case outline U as specified under paragraph 1.2.2 and figure 1. - ro	16-04-01	C. SAFFLE
H	Add device types 02 and 03. Add radiation assurance requirements, paragraph 3.1.1, and Appendix A for microcircuit die. - ro	17-01-09	C. SAFFLE
J	Revised commercial part number and CAGE information per request from OEM. Updated drawing to current requirements. Editorial changes throughout. Revised erroneous mm dimensions (reference values) for case outline Y. - cgh	25-04-23	J. ESCHMEYER



THE ORIGINAL FIRST SHEET OF THIS DRAWING HAS BEEN REPLACED.

REV	J	J																				
SHEET	23	24																				
REV	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J
SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22

Revision Status of Sheets

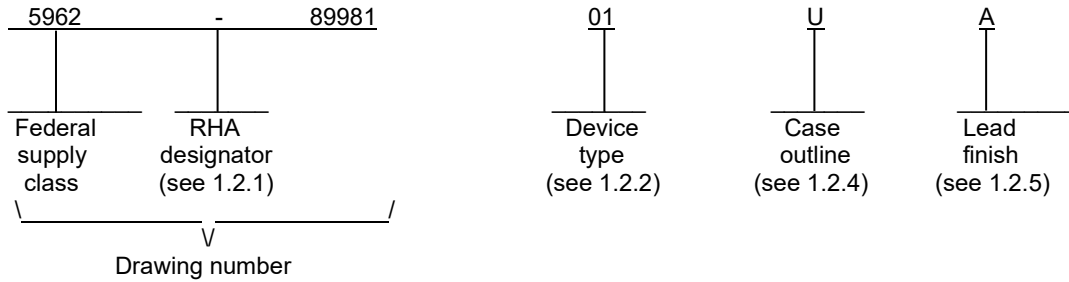
PMIC N/A		PREPARED BY JOSEPH A. KERBY		<b>DLA LAND AND MARITIME</b> <b>COLUMBUS, OHIO 43218-3990</b> <a href="https://www.dla.mil/LandandMaritime">https://www.dla.mil/LandandMaritime</a>	
<b>STANDARD MICROCIRCUIT DRAWING</b>  THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE		CHECKED BY CHARLES E. BESORE			
		APPROVED BY MICHAEL A. FRYE			
		DRAWING APPROVAL DATE 90-07-24			
AMSC N/A		REVISION LEVEL J		SIZE A	CAGE CODE <b>67268</b>
				<b>5962-89981</b>	
				SHEET 1 OF 24	

1. SCOPE

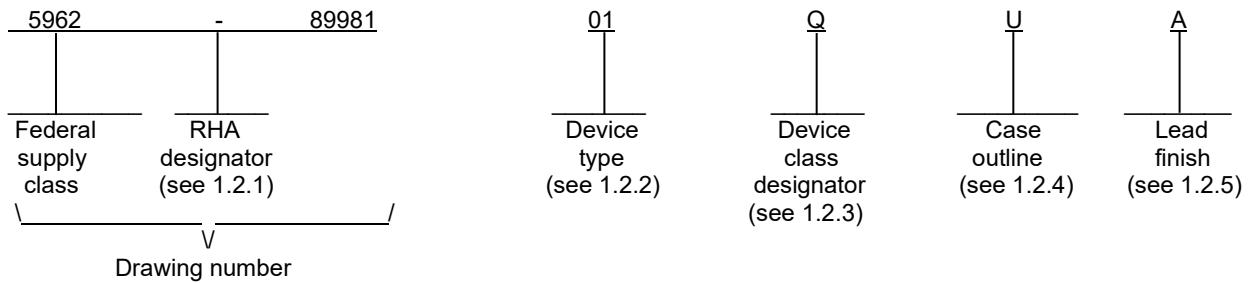
1.1 Scope. This drawing documents two product assurance class levels consisting of high reliability (device class Q and M) and space application (device class V). A choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of Radiation Hardness Assurance (RHA) levels is reflected in the PIN.

1.2 PIN. The PIN is as shown in the following example:

For device class M and Q:



For device class V:



1.2.1 RHA designator. Device classes Q and V RHA marked devices meet the MIL-PRF-38535 specified RHA levels and are marked with the appropriate RHA designator. Device class M RHA marked devices meet the MIL-PRF-38535, appendix A specified RHA levels and are marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device types. The device types identify the circuit function as follows:

Device type	Generic number	Circuit function
01	LT1086 / OM1860	Positive regulator, adjustable
02	RH1086BHK	Positive regulator, adjustable
03	RH1086BKK	Positive regulator, adjustable

1.2.3 Device class designator. The device class designator is a single letter identifying the product assurance level as listed below. Since the device class designator has been added after the original issuance of this drawing, device classes M and Q designators will not be included in the PIN and will not be marked on the device.

Device class	Device requirements documentation
M	Vendor self-certification to the requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A
Q or V	Certification and qualification to MIL-PRF-38535

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1.2.4 Case outlines. The case outlines are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
M	See figure 1	3	Flange mount, glass sealed with gull wing leads
T	CBCC1-N3	3	Bottom terminal chip carrier
U <sup>1/</sup>	See figure 1	3	TO-257 Single row flange mount with isolated tab and glass sealed
X	See figure 1	2	TO-3 Flange mount
Y	See figure 1	3	TO-39 Can
Z	See figure 1	3	Z-tab

1.2.5 Lead finish. The lead finish is as specified in MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

1.3 Absolute maximum ratings. <sup>2/</sup>

Input to output voltage differential .....	25 V dc
Output current (I <sub>MAX</sub> ):	
Device type 01:	
Cases M, T, X, U, and Z.....	1.0 A
Device types 01 and 02:	
Case Y.....	0.5 A
Device type 03:	
Case X.....	1.5 A
Power dissipation (P <sub>D</sub> ) .....	Internally limited
Junction temperature (T <sub>J</sub> ).....	+150°C
Storage temperature range .....	-65°C to +150°C
Lead temperature (soldering, 10 seconds).....	+300°C
Thermal resistance, junction-to-case (θ <sub>JC</sub> ):	
Case M.....	7.1°C/W
Case T.....	4.1°C/W
Case X.....	3.0°C/W
Cases U and Z.....	4.2°C/W
Case Y.....	40°C/W
Thermal resistance, junction-to-ambient (θ <sub>JA</sub> ):	
Case M.....	60°C/W
Case T.....	80°C/W
Case X.....	35°C/W
Cases U and Z.....	42°C/W
Case Y.....	140°C/W

1.4 Recommended operating conditions.

Input to output voltage differential .....	15 V dc
Ambient operating temperature range (T <sub>A</sub> ) .....	-55°C to +125°C

1.5 Radiation features.

For device types 02 and 03:	
Maximum total dose available (dose rate = 50 – 300 rads(Si)/s).....	100 krad(Si) <sup>3/</sup>

- <sup>1/</sup> For outline letter U, CAGE Code 57300 manufactures the TO-257 package with a ceramic seal. This applies to date code 1603 and later.
- <sup>2/</sup> Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
- <sup>3/</sup> Device types 02 and 03 may be dose rate sensitive in a space environment and may demonstrate enhanced low dose rate effects. Radiation end point limits for the noted parameters are guaranteed only for the conditions specified in MIL-STD-883, method 1019, condition A.

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## 2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

### DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

### DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.  
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

### DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.  
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <https://quicksearch.dla.mil/>.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

## 3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device classes Q and V shall be in accordance with MIL-PRF-38535 as specified herein, or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. The individual item requirements for device class M shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein.

3.1.1 Microcircuit die. For the requirements of microcircuit die, see appendix A to this document.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein for device classes Q and V or MIL-PRF-38535, appendix A and herein for device class M.

3.2.1 Case outline. The case outline shall be in accordance with 1.2.4 herein and figure 1.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.

3.2.3 Radiation exposure circuit. The radiation exposure circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing and acquiring activity upon request.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table IIA. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device. For RHA product using this option, the RHA designator shall still be marked. Marking for device classes Q and V shall be in accordance with MIL-PRF-38535. Marking for device class M shall be in accordance with MIL-PRF-38535, appendix A.

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3.5.1 Certification/compliance mark. The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-PRF-38535. The compliance mark for device class M shall be a "C" as required in MIL-PRF-38535, appendix A.

3.6 Certificate of compliance. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.6.1 herein). For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6.2 herein). The certificate of compliance submitted to DLA Land and Maritime-VA prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and herein or for device class M, the requirements of MIL-PRF-38535, appendix A and herein.

3.7 Certificate of conformance. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 or for device class M in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DLA Land and Maritime-VA of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change that affects this drawing.

3.9 Verification and review for device class M. For device class M, DLA Land and Maritime, DLA Land and Maritime's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 Microcircuit group assignment for device class M. Device class M devices covered by this drawing shall be in microcircuit group number 52 (see MIL-PRF-38535, appendix A).

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T <sub>A</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit	
					Min	Max		
Reference voltage	V <sub>REF</sub>	I <sub>OUT</sub> = 10 mA, (V <sub>IN</sub> - V <sub>OUT</sub> ) = 3.0 V	1	01, 02, 03	1.238	1.262	V	
			D, case X only	1	03	1.234		1.262
			L, case X only	1		1.225		1.262
			R, case x only	1		1.220		1.262
		1.5 V ≤ (V <sub>IN</sub> - V <sub>OUT</sub> ) ≤ 15 V, 4/ 10 mA ≤ I <sub>OUT</sub> ≤ I <sub>MAX</sub>	1, 2, 3	01, 02, 03	1.225	1.270		
			D	1	02, 03	1.220		1.275
				L		1		1.215
		R		1		1.210		1.275
		1.5 V ≤ (V <sub>IN</sub> - V <sub>OUT</sub> ) ≤ 15 V, 5/ 10 mA ≤ I <sub>OUT</sub> ≤ I <sub>MAX</sub>	1, 2, 3	01	1.220	1.270		
			Line regulation 6/	V <sub>RLINE</sub>	1.5 V ≤ (V <sub>IN</sub> - V <sub>OUT</sub> ) ≤ 15 V, I <sub>OUT</sub> = 10 mA	1, 2, 3		01, 02, 03
D	1					02, 03	0.2	
L	1	0.23						
R	1	0.25						
Load regulation 6/	V <sub>RLOAD</sub>	(V <sub>IN</sub> - V <sub>OUT</sub> ) = 3.0 V, 4/ 10 mA ≤ I <sub>OUT</sub> ≤ I <sub>MAX</sub>	1	01, 02, 03		0.3	%	
			2, 3			0.4		
		D, L, R	1	02, 03		0.3		
			(V <sub>IN</sub> - V <sub>OUT</sub> ) = 3.0 V, 5/ 10 mA ≤ I <sub>OUT</sub> ≤ I <sub>MAX</sub>	1	01			0.8
2, 3		1.0						
Dropout voltage	V <sub>DO</sub>	I <sub>OUT</sub> = I <sub>MAX</sub> , ΔV <sub>REF</sub> = 1.0%	1, 2, 3	01, 02, 03		1.5	V	
			D, case X only	1	03			1.5
				L, case X only		1		1.52
				R, case X only		1		1.55
			D, case X only	1	02			1.25
				L, case X only		1		1.27
				R, case X only		1		1.29
Thermal regulation	---	30 ms pulse, T <sub>A</sub> = +25°C	1	01, 02, 03		0.04	%/W	

See footnotes at end of table.

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SIZE  
**A**

REVISION LEVEL  
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TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>A</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Ripple rejection	ΔV <sub>IN</sub> / ΔV <sub>OUT</sub>	C <sub>ADJ</sub> = 25 μF, f = 120 Hz, C <sub>OUT</sub> = 25 μF (tantalum), I <sub>OUT</sub> = I <sub>MAX</sub> , (V <sub>IN</sub> - V <sub>OUT</sub> ) = 3.0 V	4, 5, 6	01, 02, 03	60		dB
Adjust pin current	I <sub>ADJ</sub>	1.5 V ≤ (V <sub>IN</sub> - V <sub>OUT</sub> ) ≤ 15 V, 10 mA ≤ I <sub>OUT</sub> ≤ I <sub>MAX</sub>	1, 2, 3	01, 02, 03		120	μA
			D, L, R	1	02, 03		
Adjust pin current change	ΔI <sub>ADJ</sub>	10 mA ≤ I <sub>OUT</sub> ≤ I <sub>MAX</sub> , 1.5 V ≤ (V <sub>IN</sub> - V <sub>OUT</sub> ) ≤ 15 V	1, 2, 3	01, 02, 03		5.0	μA
			D, L, R	1	02, 03		
Minimum load current	I <sub>MIN</sub>	(V <sub>IN</sub> - V <sub>OUT</sub> ) = 25 V	1, 2, 3	01, 02		10	mA
			D, L, R	1	03		
Current limit	I <sub>LIM</sub>	(V <sub>IN</sub> - V <sub>OUT</sub> ) = 5.0 V, case X only	1, 2, 3	01, 03		1.5	A
		D, L, R	1	03		1.5	
		(V <sub>IN</sub> - V <sub>OUT</sub> ) = 5.0 V <u>5/</u>	1, 2, 3	01		1.5	
		(V <sub>IN</sub> - V <sub>OUT</sub> ) = 5.0 V, case Y only	1, 2, 3	01, 02		0.5	
		D, L, R	1	02		0.5	
		(V <sub>IN</sub> - V <sub>OUT</sub> ) = 25 V, case X only	1, 2, 3	01, 03		0.05	
		D	1	03		0.05	
		L	1			0.048	
		R	1			0.047	
		(V <sub>IN</sub> - V <sub>OUT</sub> ) = 25 V <u>5/</u>	1, 2, 3	01		0.075	
		(V <sub>IN</sub> - V <sub>OUT</sub> ) = 25 V, case Y only	1, 2, 3	01, 02		0.020	
		D	1	02		0.020	
L	1		0.019				
R	1		0.018				

See footnotes at end of table.

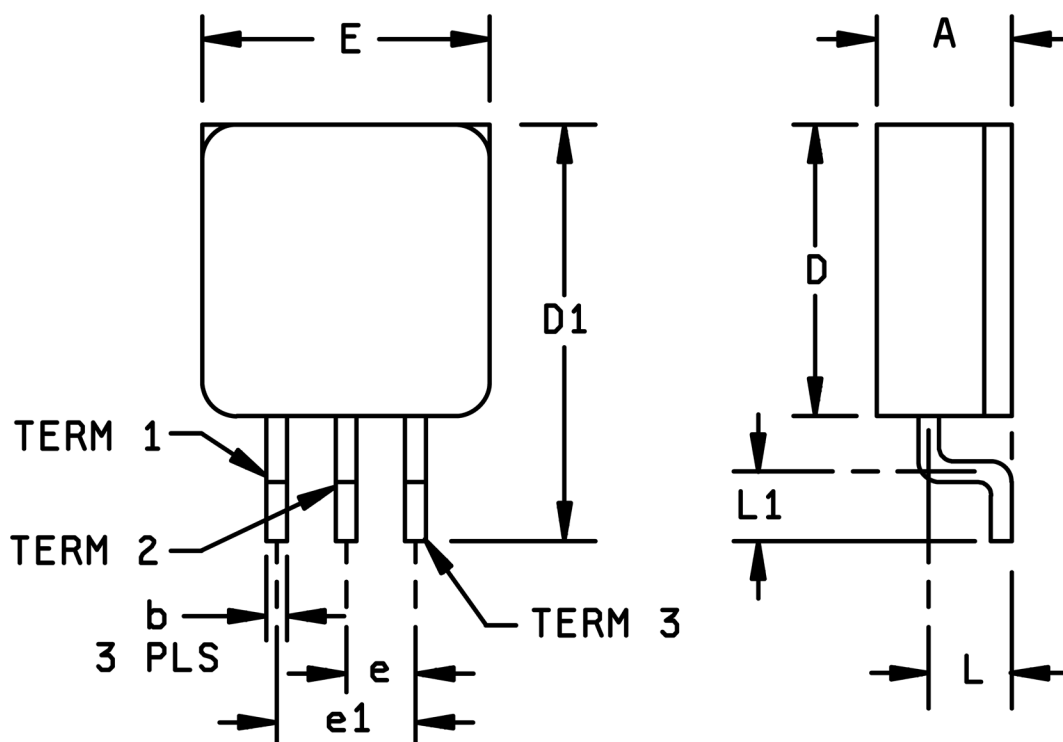
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TABLE I. Electrical performance characteristics – Continued.

- 1/ RHA devices supplied to this drawing have been characterized through all levels D, L, and R of irradiation. However, this device is tested at RHA level L and R level. Pre and Post irradiation values are identical unless otherwise specified in table I. When performing post irradiation electrical measurements for any RHA level,  $T_A = +25^{\circ}\text{C}$ .
- 2/ Device types 02 and 03 may be dose rate sensitive in a space environment and may demonstrate enhanced low dose rate effects. Radiation end point limits for the noted parameters are guaranteed only for the conditions specified in MIL-STD-883, method 1019, condition A.
- 3/ For device type 01, case outlines, M, T, X, U, and Z,  $I_{MAX} = 1.0 \text{ A}$ .  
For device types 01 and 02, case outline Y,  $I_{MAX} = 0.5 \text{ A}$ .  
For device type 03, case outline X,  $I_{MAX} = 1.5 \text{ A}$ .
- 4/ Applies to cases X and Y.
- 5/ Applies to cases M, T, U, and Z.
- 6/ Line and load regulation are measured at a constant junction temperature using a low duty cycle pulse technique. Although power dissipation is internally limited, regulation is guaranteed up to the maximum power dissipation of 15 W. Power dissipation is determined by the input/output differential voltage and the output current. Guaranteed maximum power dissipation will not be available over the full input/output voltage range.
- 7/ If not tested, shall be guaranteed to the limits specified in table I.

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Case outline M



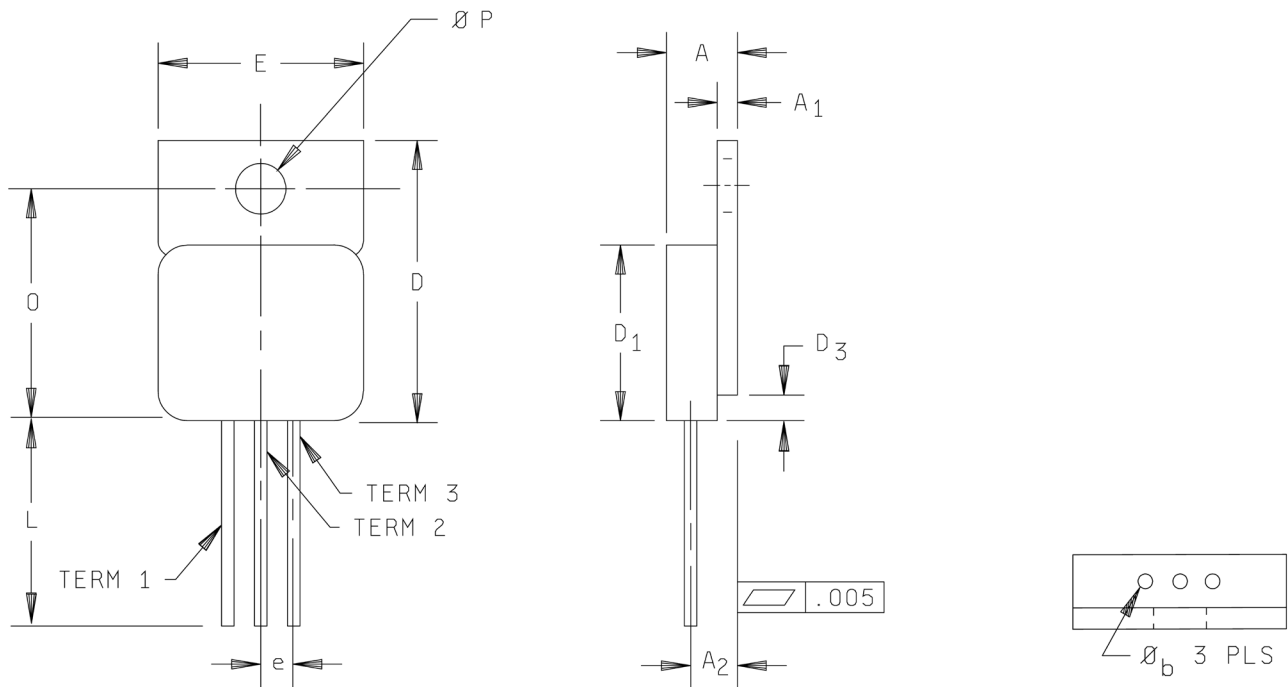
Letter	Inches		Millimeters	
	Min	Max	Min	Max
A	0.190	0.210	4.83	5.33
b	---	0.030	---	0.76
D	0.410	0.430	10.41	10.92
D1	0.580	0.610	14.73	15.49
e	---	0.100	---	2.54
e1	---	0.200	---	5.08
E	0.410	0.420	10.41	10.66
L1	0.090	0.110	2.29	2.79
L	0.115	0.125	2.92	3.17
N	3			

NOTES: 1. The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.

FIGURE 1. Case outline.

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Case outline U



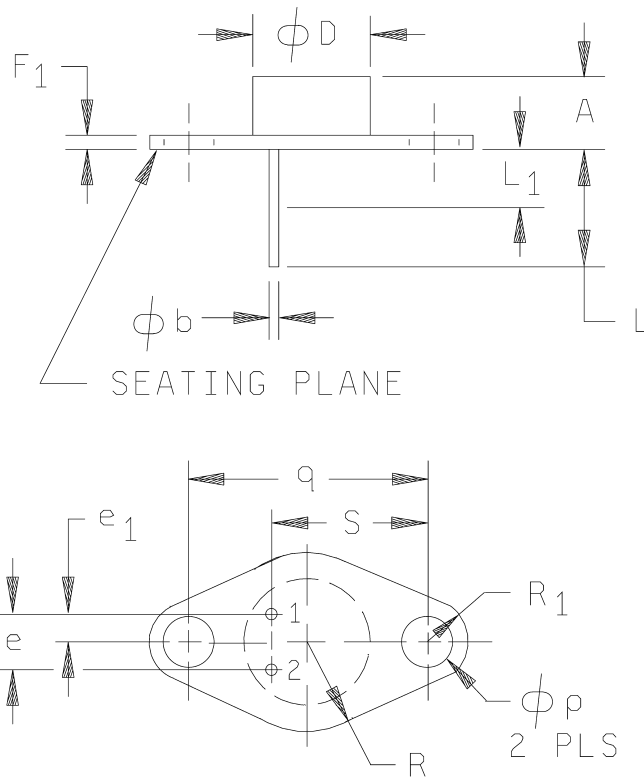
Letter	Inches		Millimeters	
	Min	Max	Min	Max
A	0.190	0.200	4.83	5.08
A <sub>1</sub>	0.035	0.045	0.89	1.14
A <sub>2</sub>	0.120 BSC		3.05 BSC	
Φb	0.025	0.035	0.64	0.89
D	0.645	0.665	16.38	16.89
D <sub>1</sub>	0.410	0.430	10.41	10.92
D <sub>3</sub>	---	0.065	---	1.65
e	0.100 BSC		2.54 BSC	
E	0.410	0.422	10.41	10.71
L	0.500	0.750	12.70	19.05
O	0.527	0.537	13.39	13.63
ΦP	0.140	0.150	3.56	3.81

- NOTES: 1. The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.
2. For outline letter U, CAGE Code 57300 manufactures the TO-257 package with a ceramic seal. This applies to date code 1603 and later.

FIGURE 1. Case outline – Continued.

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Case outline X



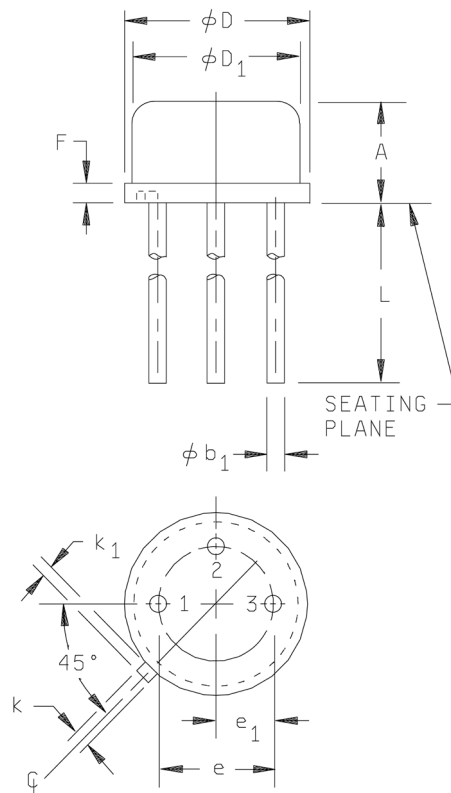
Letter	Inches		Millimeters	
	Min	Max	Min	Max
A	0.250	0.450	6.35	11.43
$\phi b$	0.038	0.043	0.97	1.09
$\phi D$	---	0.875	---	22.22
e	0.420	0.440	10.67	11.18
$e_1$	0.205	0.225	5.21	5.72
$F_1$	0.060	0.135	1.52	2.43
L	0.312	0.500	7.92	12.70
$L_1$	---	0.050	---	1.27
$\phi p$	0.151	0.161	3.84	4.09
q	1.177	1.197	29.90	30.40
R	0.495	0.525	12.57	13.34
$R_1$	0.131	0.188	3.33	4.78
S	0.655	0.675	16.64	17.15

NOTES: 1. The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.

FIGURE 1. Case outline – Continued.

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Case outline Y



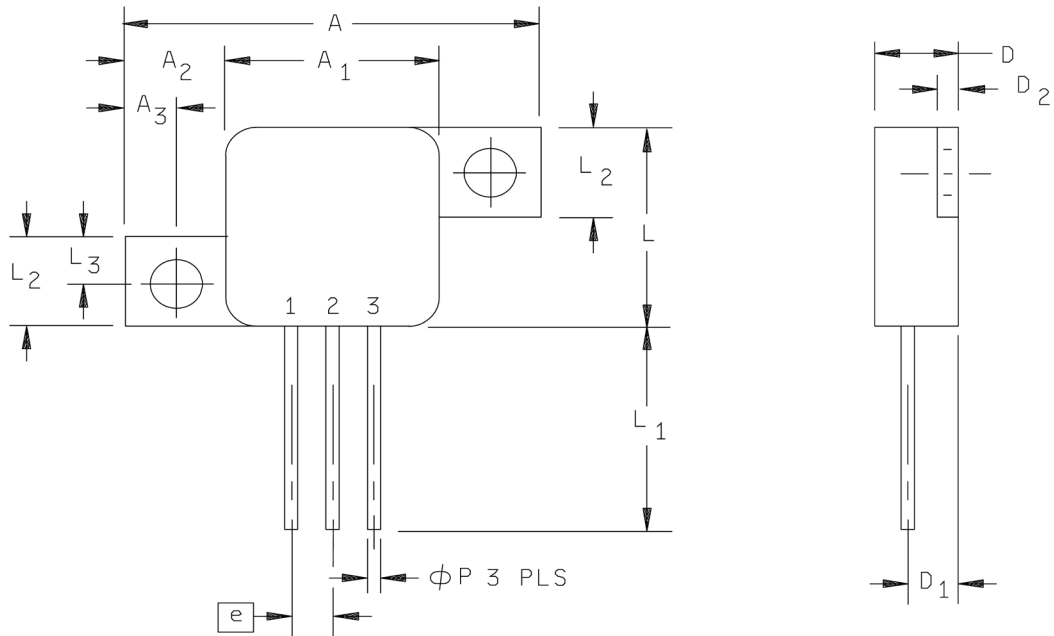
Letter	Inches		Millimeters	
	Min	Max	Min	Max
A	0.165	0.185	4.191	4.699
$\Phi b_1$	0.016	0.019	0.41	0.48
$\Phi D$	0.340	0.370	8.64	9.39
$\Phi D_1$	0.305	0.335	7.74	8.5
e	0.200 typ	NOTE 2	5.08 typ	NOTE 2
e1	0.100 typ	NOTE 2	2.54 typ	NOTE 2
F	---	0.050	---	1.27
k	0.028	0.038	0.71	0.96
k1	0.026	0.045	0.66	1.143
L	0.500	---	12.70	---

- NOTES: 1. The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.
2. Leads having a maximum diameter of 0.019 inch (0.48 mm) measured in gauging plane .054 inch  $\pm$  .001 inch (1.37 mm  $\pm$  0.03 mm) below the base plane of the product shall be within .007 inch (0.18 mm) of their true position relative to the maximum width tab.

FIGURE 1. Case outline – Continued.

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Case outline Z

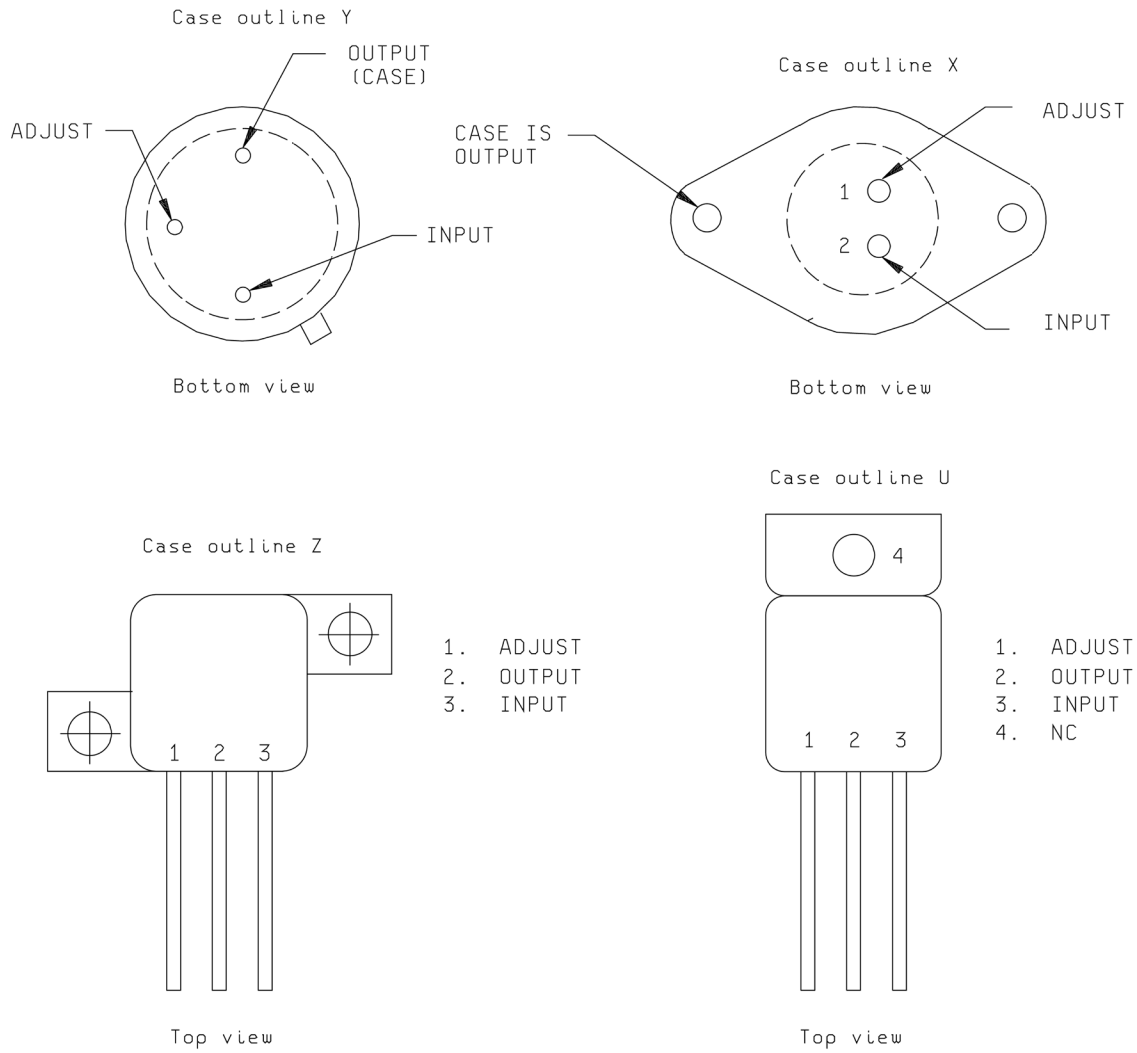


Letter	Inches		Millimeters	
	Min	Max	Min	Max
A	0.910	0.920	23.11	23.37
A <sub>1</sub>	0.410	0.420	10.41	10.67
A <sub>2</sub>	0.245	0.255	6.22	6.48
A <sub>3</sub>	0.120	0.130	3.05	3.30
$\Phi b$	0.120	0.130	3.05	3.30
D	0.135	0.220	4.70	5.59
D <sub>1</sub>	0.115	0.125	2.92	3.18
D <sub>2</sub>	0.035	0.045	0.89	1.14
e	0.100 BSC		2.54 BSC	
L	0.410	0.420	10.41	10.67
L <sub>1</sub>	0.500	0.750	12.70	19.05
L <sub>2</sub>	0.245	0.255	6.22	6.48
L <sub>3</sub>	0.120	0.130	3.05	3.30
$\Phi p$	0.028	0.032	0.71	0.81

NOTES: 1. The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.

FIGURE 1. Case outline – Continued.

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Device type	01	
Case outlines	M	T
Terminal number	Terminal symbol	
1	ADJUST	ADJUST
2	OUTPUT	INPUT
3	INPUT	OUTPUT

FIGURE 2. Terminal connections.

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COLUMBUS, OHIO 43218-3990

SIZE  
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**J**

SHEET **14**

4. VERIFICATION

4.1 Sampling and inspection. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. For device class M, sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection.

4.2.1 Additional criteria for device class M.

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
  - (2)  $T_A = +125^{\circ}\text{C}$ , minimum.
- b. Interim and final electrical test parameters shall be as specified in table IIA herein.

4.2.2 Additional criteria for device classes Q and V.

- a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table IIA herein.
- c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in MIL-PRF-38535, appendix B.

4.3 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-PRF-38535. Inspections to be performed shall be those specified in MIL-PRF-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4 Conformance inspection. Technology conformance inspection for classes Q and V shall be in accordance with MIL-PRF-38535 including groups A, B, C, D, and E inspections, and as specified herein. Quality conformance inspection for device class M shall be in accordance with MIL-PRF-38535, appendix A and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection.

- a. Tests shall be as specified in table IIA herein.
- b. Subgroups 7, 8A, 8B, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

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TABLE IIA. Electrical test requirements.

Test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)	Subgroups (in accordance with MIL-PRF-38535, table III)	
	Device class M	Device class Q	Device class V
Interim electrical parameters (see 4.2)	1	1	1, 2, 3, 4, 5, 6
Final electrical parameters (see 4.2)	1, 2, 3, 4, 5, 6 <u>1/</u>	1, 2, 3, 4, 5, 6 <u>1/</u>	1, 2, 3, 4, 5, 6 <u>1/ 2/</u>
Group A test requirements (see 4.4)	1, 2, 3, 4, 5, 6	1, 2, 3, 4, 5, 6	1, 2, 3, 4, 5, 6
Group C end-point electrical parameters (see 4.4)	1	1, 2, 3	1, 2, 3 <u>2/</u>
Group D end-point electrical parameters (see 4.4)	1	1, 2, 3	1, 2, 3
Group E end-point electrical parameters (see 4.4)	---	---	1, 4

1/ PDA applies to subgroup 1.

2/ Delta limits as specified in table IIB shall be required where specified, and the delta limits shall be completed with reference to the zero hour electrical parameters (see table I).

TABLE IIB. Burn-in and operating life test delta parameters. 1/

Parameters	Symbol	Device types	Endpoint limit		Delta limits		Units
			Min	Max	Min	Max	
Output voltage	V <sub>OUT</sub>	02, 03	1.238	1.262	-0.01	0.01	V
Adjust pin current	+IADJ		15	120	-10	10	μA
Line regulation	V <sub>RLINE</sub>		-0.2	0.2	-0.1	0.1	%

1/ T<sub>A</sub> = +25°C. Deltas are performed at room temperature

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4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
- b.  $T_A = +125^{\circ}\text{C}$ , minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.4 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein).

- a. End-point electrical parameters shall be as specified in table IIA herein.
- b. For device classes Q and V, the devices or test vehicle shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535 for the RHA level being tested. For device class M, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535, appendix A for the RHA level being tested. All device classes must meet the postirradiation end-point electrical parameter limits as defined in table I at  $T_A = +25^{\circ}\text{C} \pm 5^{\circ}\text{C}$ , after exposure, to the subgroups specified in table IIA herein.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor prepared specification or drawing.

6.1.2 Substitutability. Device class Q devices will replace device class M devices.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal, or email communication.

6.3 Record of users. Military and industrial users should inform DLA Land and Maritime when a system application requires configuration control and which SMD's are applicable to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DLA Land and Maritime-VA, telephone (614) 692-8108.

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6.4 Comments. Comments on this drawing should be directed to DLA Land and Maritime-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0591.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535 and MIL-HDBK-1331.

6.6 Sources of supply.

6.6.1 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in MIL-HDBK-103 and QML-38535. The vendors listed in MIL-HDBK-103 and QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DLA Land and Maritime-VA and have agreed to this drawing.

6.6.2 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DLA Land and Maritime-VA.

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APPENDIX A  
APPENDIX A FORMS A PART OF SMD 5962-89981

A.1.2.4 Die details. The die details designation is a unique letter which designates the die's physical dimensions, bonding pad location(s) and related electrical function(s), interface materials, and other assembly related information, for each product and variant supplied to this appendix.

A.1.2.4.1 Die physical dimensions.

<u>Die type</u>	<u>Figure number</u>
02	A-1
03	A-2

A.1.2.4.2 Die bonding pad locations and electrical functions.

<u>Die type</u>	<u>Figure number</u>
02	A-1
03	A-2

A.1.2.4.3 Interface materials.

<u>Die type</u>	<u>Figure number</u>
02	A-1
03	A-2

A.1.2.4.4 Assembly related information.

<u>Die type</u>	<u>Figure number</u>
02	A-1
03	A-2

A.1.2.4.5 Special handling of dice. Radiation hardened dice require special handling as compared to standard integrated circuit dice. Radiation hardened dice are susceptible to surface damage due to the absence of silicon nitride passivation that is present on most standard dice. Silicon nitride protects the dice surface from scratches by its hard and dense properties. The passivation on radiation hardened dice is silicon dioxide which is much "softer" than silicon nitride. During the visual and preparation for shipment, electrostatic discharge (ESD) safe tweezers are used and only the edge of the die are touched.

It is recommended that dice handling be performed with extreme care so as to protect the die surface from scratches. If the need arises to move the die in or out of the chip shipment tray (waffle pack), use an ESD safe plastic tipped bent metal vacuum probe, preferably .020 inch outside diameter x .010 inch inside diameter (for use with tiny parts). The wand should be compatible with continuous air vacuums. The tip material should be static dissipative Delrin (or equivalent) plastic.

During die attach, care must be exercised to ensure no tweezers, or other equipment, touch the top of the dice.

A.1.3 Absolute maximum ratings. See paragraph 1.3 herein for details.

A.1.4 Recommended operating conditions. See paragraph 1.4 herein for details.

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A.2 APPLICABLE DOCUMENTS

A.2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARD

MIL-STD-883 - Test Method Standard Microcircuits.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.

MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <https://quicksearch.dla.mil> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

A.2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

A.3 REQUIREMENTS

A.3.1 Item requirements.

A.3.2 Design, construction and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein and the manufacturer's QM plan for device classes Q and V.

A.3.2.1 Die physical dimensions. The die physical dimensions shall be as specified in A.1.2.4.1 and on figures A-1 and A-2.

A.3.2.2 Die bonding pad locations and electrical functions. The die bonding pad locations and electrical functions shall be as specified in A.1.2.4.2 and on figures A-1 and A-2.

A.3.2.3 Interface materials. The interface materials for the die shall be as specified in A.1.2.4.3 and on figures A-1 and A-2.

A.3.2.4 Assembly related information. The assembly related information shall be as specified in A.1.2.4.4 and on figures A-1 and A-2.

A.3.2.5 Radiation exposure circuit. The radiation exposure circuit shall be as defined in paragraph 3.2.3 herein.

A.3.3 Electrical performance characteristics and post-irradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and post-irradiation parameter limits are as specified in table I of the body of this document.

A.3.4 Electrical test requirements. The wafer probe test requirements shall include functional and parametric testing sufficient to make the packaged die capable of meeting the electrical performance requirements in table I.

A.3.5 Marking. As a minimum, each unique lot of die, loaded in single or multiple stack of carriers, for shipment to a customer, shall be identified with the wafer lot number, the certification mark, the manufacturer's identification and the PIN listed in A.1.2 herein. The certification mark shall be a "QML" or "Q" as required by MIL-PRF-38535.

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A.3.6 Certification of compliance. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see A.6.4 herein). The certificate of compliance submitted to DLA Land and Maritime -VA prior to listing as an approved source of supply for this appendix shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and the requirements herein.

A.3.7 Certificate of conformance. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 shall be provided with each lot of microcircuit die delivered to this drawing.

A.4 VERIFICATION

A.4.1 Sampling and inspection. For device classes Q and V, die sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modifications in the QM plan shall not affect the form, fit, or function as described herein.

A.4.2 Screening. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and as defined in the manufacturer's QM plan. As a minimum, it shall consist of:

- a. Wafer lot acceptance for class V product using the criteria defined in MIL-STD-883, method 5007.
- b. 100% wafer probe (see paragraph A.3.4 herein).
- c. 100% internal visual inspection to the applicable class Q or V criteria defined in MIL-STD-883, method 2010 or the alternate procedures allowed in MIL-STD-883, method 5004.

A.4.3 Conformance inspection.

A.4.3.1 Group E inspection. Group E inspection is required only for parts intended to be identified as radiation assured (see A.3.5 herein). RHA levels for device classes Q and V shall be as specified in MIL-PRF-38535. End point electrical testing of packaged die shall be as specified in table IIA herein. Group E tests and conditions are as specified in paragraphs 4.4.4 and 4.4.4.1 herein.

A.5 DIE CARRIER

A.5.1 Die carrier requirements. The requirements for the die carrier shall be accordance with the manufacturer's QM plan or as specified in the purchase order by the acquiring activity. The die carrier shall provide adequate physical, mechanical and electrostatic protection.

A.6 NOTES

A.6.1 Intended use. Microcircuit die conforming to this drawing are intended for use in microcircuits built in accordance with MIL-PRF-38535 or MIL-PRF-38534 for government microcircuit applications (original equipment), design applications, and logistics purposes.

A.6.2 Comments. Comments on this appendix should be directed to DLA Land and Maritime -VA, Columbus, Ohio, 43218-3990 or telephone (614)-692-0540.

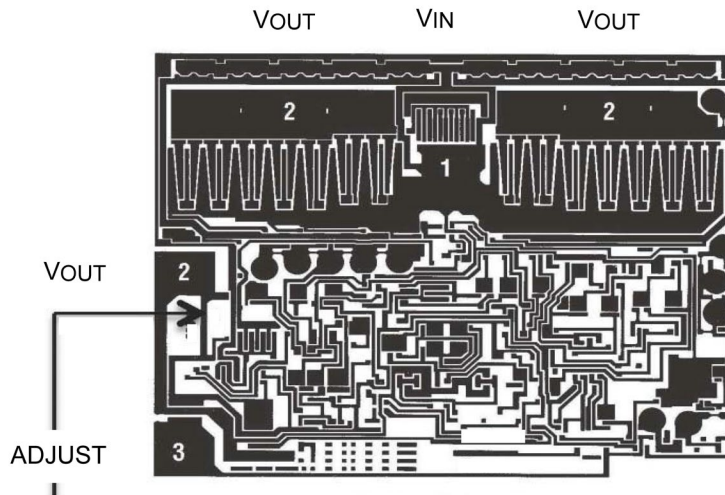
A.6.3 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535 and MIL-HDBK-1331.

A.6.4 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in MIL-HDBK-103 and QML-38535. The vendors listed within MIL-HDBK-103 and QML-38535 have submitted a certificate of compliance (see A.3.6 herein) to DLA Land and Maritime-VA and have agreed to this drawing.

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Device type 02



For device type 02, a "H" will be specified here on the die.

Die bonding pad locations and electrical functions for device type 02.

Die physical dimensions.

Die size: 103 mils x 85 mils

Die thickness: 12 mils

Interface materials.

Top metallization: AlSi 1% Cu 0.5%

Backside metallization: Au

Glassivation.

Type: SiO<sub>2</sub>

Thickness: 4 kÅ

Substrate: Single crystal silicon

Assembly related information.

Substrate potential: VOUT

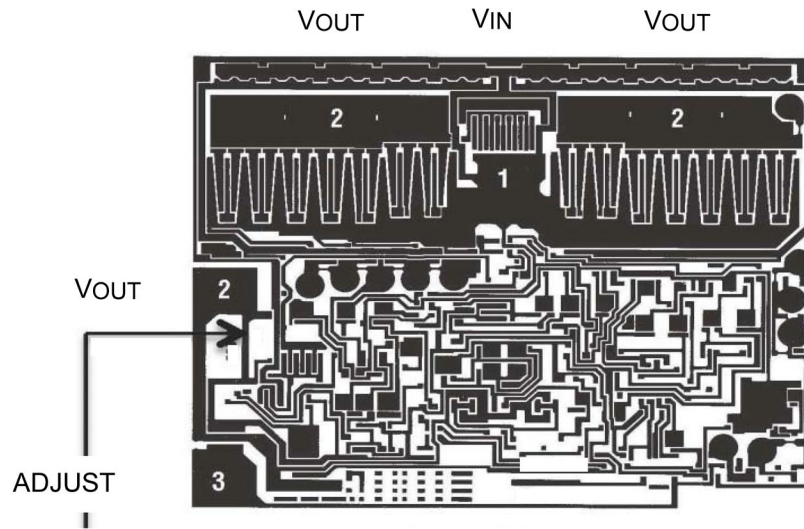
Special assembly instructions: Connect backside substrate to pad number 2.

FIGURE A-1. Die bonding pad locations and electrical functions.

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Device type 03



For device type 03, a "K" will be specified here on the die.

Die bonding pad locations and electrical functions for device type 03.

Die physical dimensions.

Die size: 103 mils x 85 mils  
 Die thickness: 12 mils

Interface materials.

Top metallization: AlSi 1% Cu 0.5%  
 Backside metallization: Au

Glassivation.

Type: SiO<sub>2</sub>  
 Thickness: 4 kÅ

Substrate: Single crystal silicon

Assembly related information.

Substrate potential: VOUT  
 Special assembly instructions: Connect backside substrate to pad number 2.

FIGURE A-2. Die bonding pad locations and electrical functions.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 25-04-23

Approved sources of supply for SMD 5962-89981 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DLA Land and Maritime maintains an online database of all current sources of supply at <https://landandmaritimeapps.dla.mil/programs/smcr/>.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-8998101MA	57300	MTLT1086QU
	<u>3/</u>	OM1860SRM
5962-8998101TA	<u>3/</u>	OM1860N5M
5962-8998101UA	57300	MTLT1086QP
	<u>3/</u>	SDP1086UMD
	<u>3/</u>	OM1860STM
	<u>3/</u>	FM186S7
5962-8998101XA	57300	MTLT1086QK
	<u>3/</u>	MTLT1086QK
	<u>3/</u>	SDP1086XMD
	<u>3/</u>	OM1860NKM
	<u>3/</u>	LT1086MK/883
5962-8998101YA	57300	MTLT1086QH
	<u>3/</u>	SDP1086YMD
	<u>3/</u>	OM1860NHM
	<u>3/</u>	LT1086MH/883
5962-8998101ZA	57300	MTLT1086QZ
	<u>3/</u>	SDP1086ZMD
	<u>3/</u>	OM1860STZM
5962R8998102VYA	24355	RH1086MH
5962R8998103VXA	<u>3/</u>	RH1086MK
5962R8998102V9A	<u>3/</u>	RH1086BHK
5962R8998103V9A	<u>3/</u>	RH1086BKK

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed, contact the vendor to determine its availability.
- 2/ **Caution.** Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source of supply. Last known suppliers are listed on the next page of this bulletin.

STANDARD MICROCIRCUIT DRAWING BULLETIN - CONTINUED

DATE: 25-04-23

<u>Vendor CAGE number</u>	<u>Vendor name and address</u>
57300	Micross Components 7725 N. Orange Blossom Trail Orlando, FL 32810-2696
60264	Minco Technology Labs, Inc. 1805 Rutherford Lane Austin, TX 78754-5101
24355	Analog Devices, Inc. 1 Analog Way Wilmington, MA 01887-2356

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.